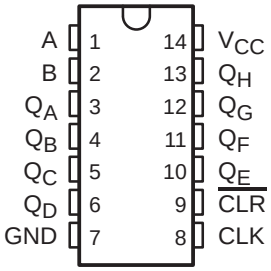
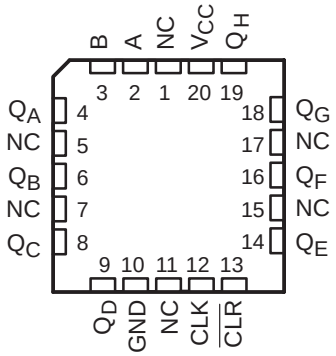
- **AND-Gated (Enable/Disable) Serial Inputs**
- **Fully Buffered Clock and Serial Inputs**
- **Direct Clear**
- **Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs**

SN54HC164 . . . J OR W PACKAGE
SN74HC164 . . . D OR N PACKAGE
(TOP VIEW)



SN54HC164 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

description

These 8-bit shift registers feature AND-gated serial inputs and an asynchronous clear ($\overline{CLR}$) input. The gated serial (A and B) inputs permit complete control over incoming data; a low at either input inhibits entry of the new data and resets the first flip-flop to the low level at the next clock (CLK) pulse. A high-level input enables the other input, which then determines the state of the first flip-flop. Data at the serial inputs can be changed while CLK is high or low, provided the minimum setup time requirements are met. Clocking occurs on the low-to-high-level transition of CLK.

The SN54HC164 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC164 is characterized for operation from –40°C to 85°C.

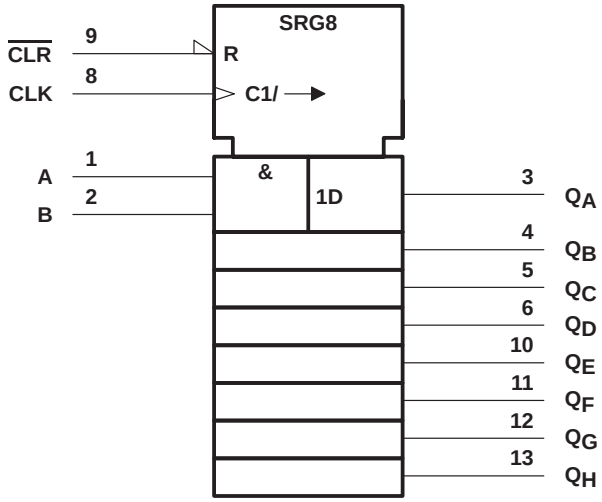
FUNCTION TABLE

INPUTS				OUTPUTS		
$\overline{CLR}$	CLK	A	B	Q_A	$Q_B \cdots Q_H$	
L	X	X	X	L	L	L
H	L	X	X	Q_{A0}	Q_{B0}	Q_{H0}
H	↑	H	H	H	Q_{An}	Q_{Gn}
H	↑	L	X	L	Q_{An}	Q_{Gn}
H	↑	X	L	L	Q_{An}	Q_{Gn}

Q_{A0}, Q_{B0}, Q_{H0} = the level of Q_A, Q_B, or Q_H, respectively, before the indicated steady-state input conditions were established

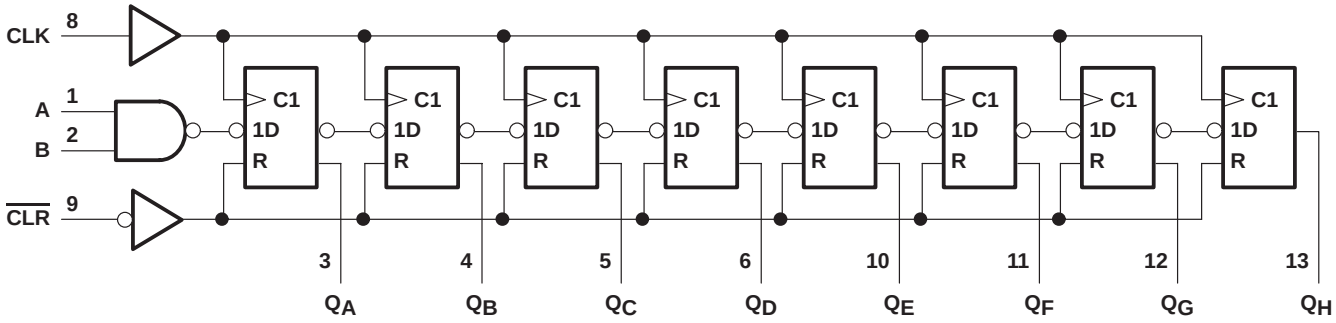
Q_{An}, Q_{Gn} = the level of Q_A or Q_G before the most recent ↑ transition of CLK: indicates a 1-bit shift

logic symbol†



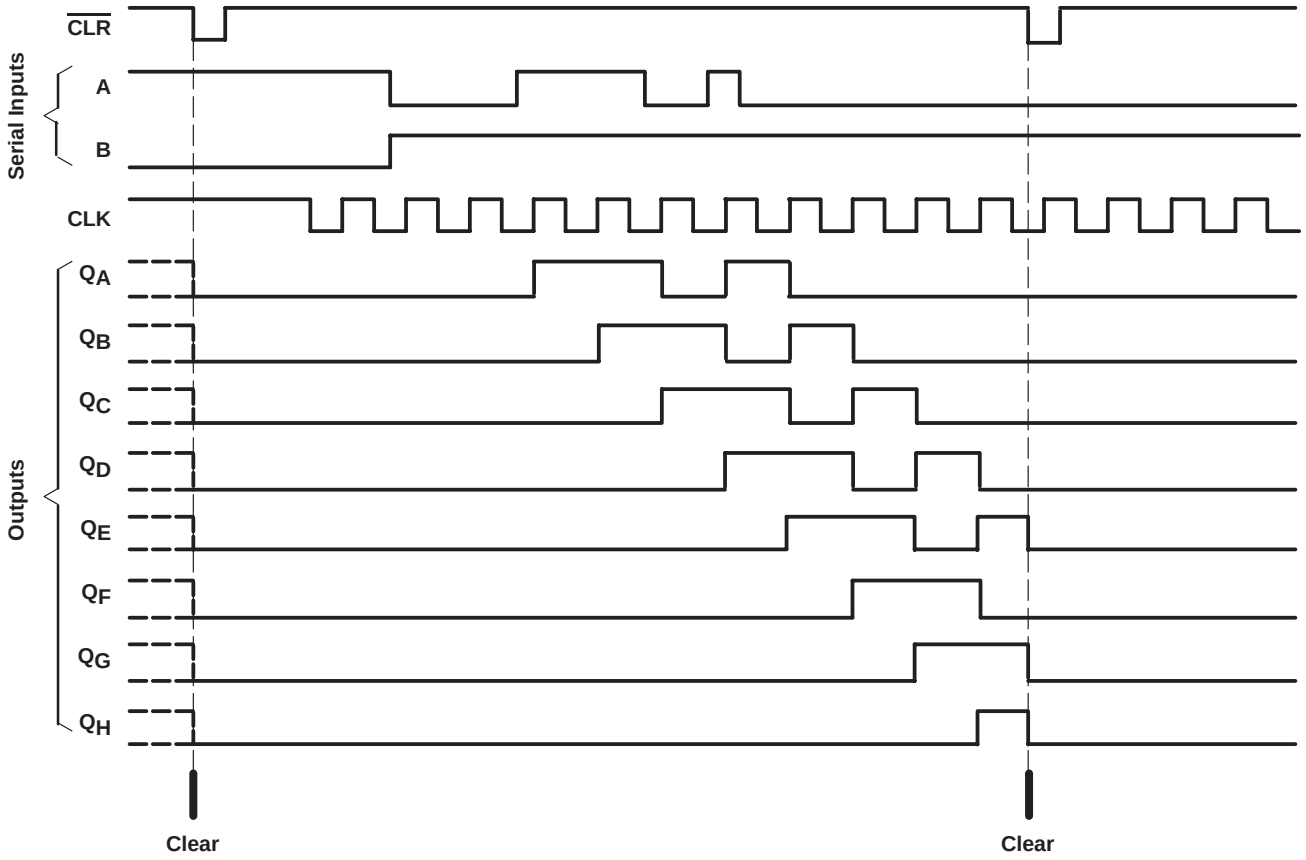
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, J, N, and W packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

typical clear, shift, and clear sequence



absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±25 mA
Continuous current through V_{CC} or GND	±50 mA
Package thermal impedance, θ_{JA} (see Note 2): D package	127°C/W
N package	78°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN54HC164			SN74HC164			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		2	5	6	2	5	6	V
V_{IH}	High-level input voltage	V_{CC} = 2 V	1.5			1.5			V
		V_{CC} = 4.5 V	3.15			3.15			
		V_{CC} = 6 V	4.2			4.2			
V_{IL}	Low-level input voltage	V_{CC} = 2 V	0		0.5	0		0.5	V
		V_{CC} = 4.5 V	0		1.35	0		1.35	
		V_{CC} = 6 V	0		1.8	0		1.8	
V_I	Input voltage		0		V_{CC}	0		V_{CC}	V
V_O	Output voltage		0		V_{CC}	0		V_{CC}	V
t_t†	Input transition (rise and fall) time	V_{CC} = 2 V	0		1000	0		1000	ns
		V_{CC} = 4.5 V	0		500	0		500	
		V_{CC} = 6 V	0		400	0		400	
T_A	Operating free-air temperature		–55		125	–40		85	°C

† If this device is used in the threshold region (from V_{IL}max = 0.5 V to V_{IH}min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t_t = 1000 ns and V_{CC} = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V_{CC}	T_A = 25°C			SN54HC164		SN74HC164		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}	V_I = V_{IH} or V_{IL}	I_{OH} = –20 μA	2 V	1.9	1.998		1.9		1.9		V
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		I_{OH} = –4 mA	4.5 V	3.98	4.3		3.7		3.84		
		I_{OH} = –5.2 mA	6 V	5.48	5.8		5.2		5.34		
V_{OL}	V_I = V_{IH} or V_{IL}	I_{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
			6 V		0.001	0.1		0.1		0.1	
		I_{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I_{OL} = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
I_I	V_I = V_{CC} or 0		6 V		±0.1	±100		±1000		±1000	nA
I_{CC}	V_I = V_{CC} or 0,	I_O = 0	6 V			8		160		80	μA
C_i			2 V to 6 V		3	10		10		10	pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			V_{CC}	T_A = 25°C		SN54HC164		SN74HC164		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency		2 V	0	6	0	4.2	0	5	MHz
			4.5 V	0	31	0	21	0	25	
			6 V	0	36	0	25	0	28	
t_w	Pulse duration	$\overline{CLR}$ low	2 V	100		150		125		ns
			4.5 V	20		30		25		
			6 V	17		25		21		
		CLK high or low	2 V	80		120		100		
			4.5 V	16		24		20		
			6 V	14		20		18		
t_{su}	Setup time before CLK↑	Data	2 V	100		150		125		ns
			4.5 V	20		30		25		
			6 V	17		25		21		
		$\overline{CLR}$ inactive	2 V	100		150		125		
			4.5 V	20		30		25		
			6 V	17		25		21		
t_h	Hold time, data after CLK↑		2 V	5		5		5		ns
			4.5 V	5		5		5		
			6 V	5		5		5		

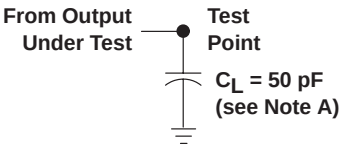
switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	T_A = 25°C			SN54HC164		SN74HC164		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{max}			2 V	6	10		4.2		5		MHz
			4.5 V	31	54		21		25		
			6 V	36	62		25		28		
t_{PHL}	$\overline{CLR}$	Any Q	2 V		140	205		295		255	ns
			4.5 V		28	41		59		51	
			6 V		24	35		51		46	
t_{pd}	CLK	Any Q	2 V		115	175		265		220	
			4.5 V		23	35		53		44	
			6 V		20	30		45		38	
t_t			2 V		38	75		110		95	ns
			4.5 V		8	15		22		19	
			6 V		6	13		19		16	

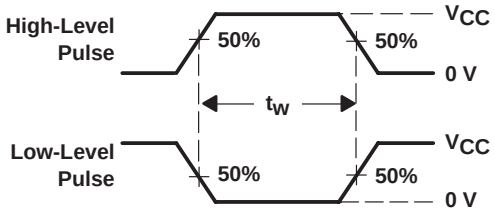
operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance	No load	135	pF

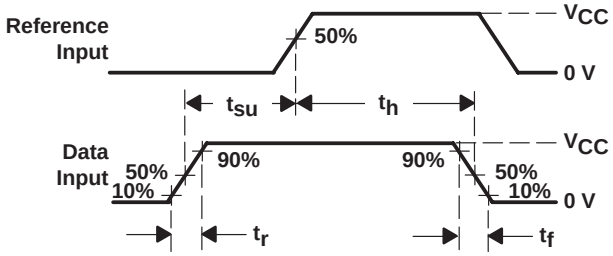
PARAMETER MEASUREMENT INFORMATION



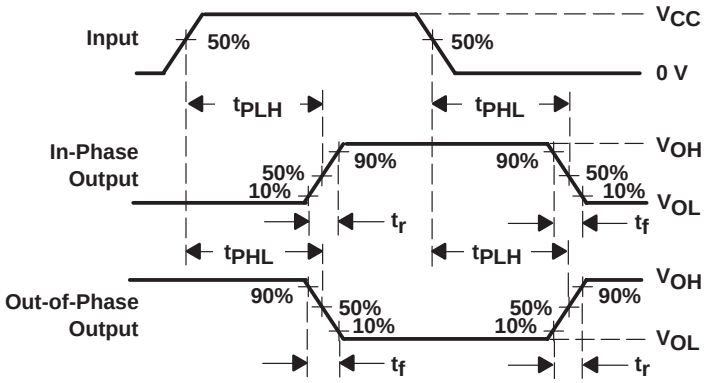
LOAD CIRCUIT



VOLTAGE WAVEFORMS
PULSE DURATIONS



VOLTAGE WAVEFORMS
SETUP AND HOLD AND INPUT RISE AND FALL TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

NOTES: A. C_L includes probe and test-fixture capacitance.
B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r = 6 ns, t_f = 6 ns.
C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
D. The outputs are measured one at a time with one input transition per measurement.
E. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

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